Measurement of: I-V Measurement

Equipment: I-V Measurement (Keithley 4200SCS)

Property Measured:

Electrical Characterization is usually performed on the Two basic device types
Transistors -BJT, MOS, IGBT etc.
Diodes -PN, Schottky, Gated etc.

Photograph (small size)

Basic Principle: Model 4200 Semi Conductor Characterization System(SCS) is used to measure DC I-V of two terminal and three terminal semiconductor devices . The system supports up to Two Source-Measure Units. Electrical Characterization is usually performed on the Two basic device types
Transistors -BJT, MOS, IGBT etc.
Diodes -PN, Schottky, Gated etc.

Capabilities: The instrument can do the I-V measurement of thin film/bulk sample

Sample Requirement: thin film/bulk sample